# Notice of References Cited Application/Control No. | Applicant(s)/Patent Under | Reexamination | ITO, HISAYOSHI | Examiner | Art Unit | Page 1 of 4

# **U.S. PATENT DOCUMENTS**

*	-	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-4,822,535 A	04-1989	Ekman et al.	264/4.3
*	В	US-5,096,492 A	03-1992	Fuisz, Richard C.	106/217.7
*	С	US-5,104,914 A	04-1992	Elton et al.	524/22
*	D	US-5,945,245 A	08-1999	Mychajlowskij et al.	430/137.14
*	E	US-5,961,711 A	10-1999	Saikatsu et al.	106/498
*	F	US-5,964,938 A	10-1999	Balliello, Paolo	106/493
*	G	US-5,961,710 A	10-1999	Linde et al.	. 106/437
*	Н	US-5,985,019 A	11-1999	McCrae et al.	106/413
*	ı	US-6,211,347 B1	04-2001	Sieber et al.	. 534/801
*	J	US-6,267,812 B1	07-2001	Lefer et al.	106/487
*	К	US-2001/0021733 A1	09-2001	Peltonen et al.	524/47
*	L	US-6,294,013 B1	09-2001	Ortlano et al.	106/499
*	М	US-6,299,676 B1	10-2001	Saikatsu et al.	106/31.77

# **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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# **NON-PATENT DOCUMENTS**

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited Application/Control No. 10/580,605 Examiner Liam J. Heincer Applicant(s)/Patent Under Reexamination ITO, HISAYOSHI Page 2 of 4

# **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2001/0026898 A1	10-2001	Tomita, Kunihiko	430/108.4
*	В	US-6,419,830 B2	07-2002	Strom et al.	210/645
*	С	US-6,468,341 B2	10-2002	Wada et al.	106/413
*	D	US-6,471,766 B2	10-2002	Ohki et al.	106/498
*	Ε	US-6,518,334 B1	02-2003	Calhoun et al.	524/47
*	F	US-2003/0049559 A1	03-2003	Shigemori et al.	430/137.18
*	G	US-6,548,170 B2	04-2003	Perrier et al.	428/402
*	Н	US-6,548,579 B2	04-2003	Reski et al.	524/47
*	ı	US-2003/0157421 A1	08-2003	Matsushima et al.	430/124
*	J	US-2003/0188664 A1	10-2003	Anantharaman et al.	106/493
*	К	US-6,641,656 B2	11-2003	Yu et al.	106/493
*	L	US-6,669,771 B2	12-2003	Tokiwa et al.	106/162.7
*	М	US-6,736,892 B2	05-2004	Godwin et al.	106/499

# FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited

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Examiner	Art Unit			
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# U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,753,377 B1	06-2004	Niinikoski et al.	524/734
*	В	US-2004/0127601 A1	07-2004	Sano et al.	523/160
*	С	US-6,780,903 B2	08-2004	Peltonen et al.	524/47
*	D	US-6,784,231 B2	08-2004	Shimada et al.	524/93
*	Ε	US-6,786,965 B2	09-2004	Perry et al.	106/491
*	F	US-2004/0181009 A1	09-2004	Shelton et al.	525/054.3
*	G	US-6,800,675 B1	10-2004	Pfalz et al.	524/47
*	Н	US-6,800,127 B2	10-2004	Babler, Fridolin	106/493
*	ı	US-6,825,252 B2	11-2004	Helbling et al.	524/47
*	J	US-2004/0266911 A1	12-2004	Aida et al.	523/160
*	Ķ	US-2005/0176878 A1	08-2005	Ettl et al.	524/571
*	L	US-6,936,097 B2	08-2005	Shakhnovich, Alex I.	106/493
*	М	US-2005/0208005 A1	09-2005	Giroud, Franck	424/070.1

# **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N.					
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# **NON-PATENT DOCUMENTS**

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

# Notice of References Cited

Application/Control No. 10/580,605	Reexamination	Applicant(s)/Patent Under Reexamination ITO, HISAYOSHI		
Examiner	Art Unit			
Liam I Heincer	1709	Page 4 of 4		

# **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,939,536 B2	09-2005	Chen et al.	424/70.1
*	В	US-6,962,950 B1	11-2005	Bastioli et al.	524/47
*	С	US-2006/0039936 A1	02-2006	Fares et al.	424/401
*	D	US-2006/0239946 A1	10-2006	Samain et al.	424/063
*	Е	US-2006/0286168 A1	12-2006	Koike et al.	424/470
*	F	US-2007/0037900 A1	02-2007	Harada et al.	523/160
*	G	US-7,192,477 B2	03-2007	Nakanishi et al.	106/412
*	Н	US-7,217,488 B2	05-2007	Mikuriya et al.	430/110.2
*	ı	US-2007/0104951 A1	05-2007	Ito, Hisayoshi	428/402.2
	J	US-			
	К	US-			·
	L	US-			
	М	US-			

# **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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# NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.